

ISO 22493:2014-04 (E)

Microbeam analysis - Scanning electron microscopy - Vocabulary

Contents		Page
Foreword		iv
Introduction		v
1 Scope		1
2 Abbreviated terms		1
3 Terms and definitions used in the physical basis of SEM		1
4 Terms and definitions used in SEM instrumentation		5
5 Terms and definitions used in SEM image formation and processing		12
6 Terms and definitions used in SEM image interpretation and analysis		16
7 Terms and definitions used in the measurement and calibration of SEM image magnification and resolution		18
Bibliography		20